



## NI SEMICONDUCTOR EXCHANGE - OCTOBER 30, 2020 (APAC)

### Live Sessions Schedule

Keynote			
10:00–10:30 a.m.	<b>The Future of Semi Test: Applying Digital Transformation Technologies to Semiconductor Product Development</b> Ritu Favre, NI		
	Mixed Signal Track	Wireless Track	Enterprise Track
10:30–11:00 a.m.	<b>Simplify Semiconductor Device Control</b> Mike Watts, NI Marvin Landrum, NI	<b>Achieve Lab-Grade RFFE Validation Results with Production Test Speed</b> Alejandro Buritica, NI	<b>Break Down Barriers From Design to Test</b> George Zafiropoulos, NI
11:00–11:10 a.m.	Break		
11:10–11:40 a.m.	<b>Optimize Semiconductor Power Efficiency Measurements</b> Mike Watts, NI	<b>Future of Connectivity: Wifi6 and Wifi7</b> Alejandro Buritica, NI	
11:40 a.m.–12:10 p.m.	<b>Improve WLR System Performance to Enhance Your Reliability Decisions</b> Joris Donders, NI Karen Armendariz, Celadon Eric Wilcox, FormFactor	<b>Address the Challenges of 5G OTA Validation from DFF to IFF</b> Alejandro Buritica, NI	<b>From 5G to 6G: Understanding the Next Generation of Mobile Communications</b> Moderator: David Hall, NI Key panelists: Dr. Volker Ziegler, 6G Leadership Nokia Bell Labs & CTO Joe Madden, President of Mobile Experts Charles Schroeder, Head of Wireless Long Term Development Initiatives and Fellow at NI
12:10–12:20 p.m.	Break		
12:20–12:50 p.m.	<b>Tips and Tricks for Better SMU Measurements</b> Austin Stanton, NI	<b>Accelerate 5G mmWave Beamformer Test</b> Yuka Muto, NI Mike Mayberry, NI	<b>Ways to Improve Operational Efficiency of Your V&amp;V Labs</b> Ray Hsu, NI
12:50–1:20 p.m.		<b>Speed Up Your Load Pull Test</b> Vince Mallette, Focus Microwaves	<b>Enable Machine Learning Approaches to Semiconductor Data</b> Alon Malki, NI

[For abstract and full list of on-demand sessions, please click here.](#)

*\*Please note that this agenda is still subject to change.*